

## PALM INTRANET

Day: Thursday Date: 11/20/2003

Time: 11:11:14

## **Inventor Name Search Result**

Your Search was:

Last Name = ISOGAI First Name = SEIJI

Application#	Patent#	Status	Date Filed	Title	Inventor Name 9
10342871	Not Issued	041		PROCESS MANAGEMENT SYSTEM	ISOGAI, SEIЛ
10096917	Not Issued	030	03/14/2002	REVIEW WORK SUPPORTING SYSTEM	ISOGAI, SEIJI
09794532	Not Issued	061	02/27/2001	METHOD FOR INSPECTING DEFECT AND SYSTEM THEREFOR	ISOGAI, SEIJI
<u>09783604</u>	Not Issued	030	02/15/2001	A METHOD AND SYSTEM FOR ANALYZING CIRCUIT PATTERN DEFECTS	ISOGAI, SEIJI
09743560	Not Issued	061	01/09/2001	METHOD FOR OBSERVING SPECIMEN AND DEVICE THEREFOR	ISOGAI, SEIЛ
09716077	Not Issued	030	11/17/2000	DEFECT IMAGE CLASSIFYING METHOD AND APPARATUS AND A SEMICONDUCTOR DEVICE MANUFACTURING PROCESS BASED ON THE METHOD AND APPARATUS	ISOGAI, SEIJI
09452149	Not Issued	061	12/01/1999	INSPECTING METHOD, INSPECTING SYSTEM, AND METHOD FOR MANUFACTURING ELECTRONIC DEVICES	ISOGAI, SEIЛ
<u>09421093</u>	6476388	150	10/19/1999	SCANNING ELECTRON MICROSCOPE, DEFECT PORTION ANALYZING METHOD USING THE SAME AND APPARATUS AND METHOD OF AUTOMATICALLY SAMPLING IMAGE THEREOF	ISOGAI , SEIJI
09142546	6542830	150	09/10/1998	PROCESS CONTROL SYSTEM	ISOGAI , SEIJI

## Inventor Search Completed: No Records to Display.

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